

Supplementary Information for

Microsphere-coupled light emission control of van der Waals heterostructures

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Transition metal dichalcogenide, Microsphere, Purcell effect, Light-emitting transistor

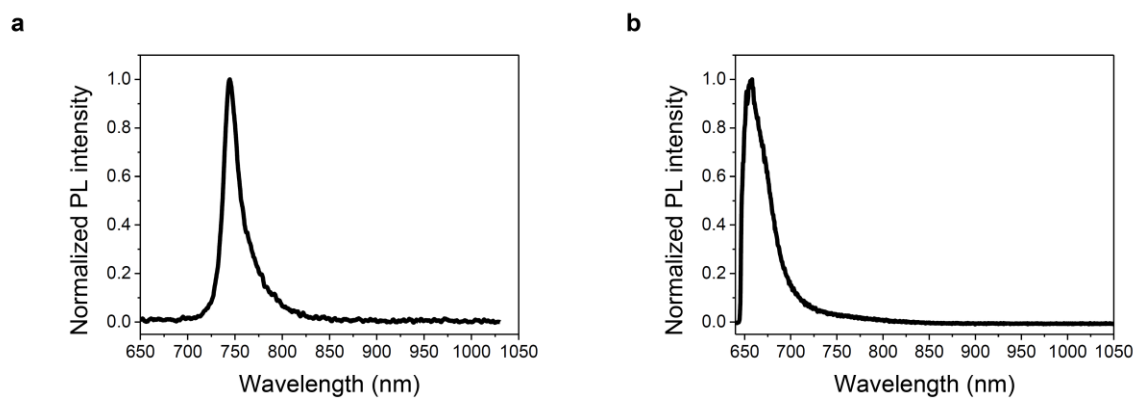


Fig. S1 (a) Photoluminescence spectrum of monolayer WSe₂ showing the absence of the indirect gap emission. **(b)** Photoluminescence spectrum of monolayer MoS₂ showing the absence of the indirect gap emission. Both spectra are measured using the optical pump at 532 nm.

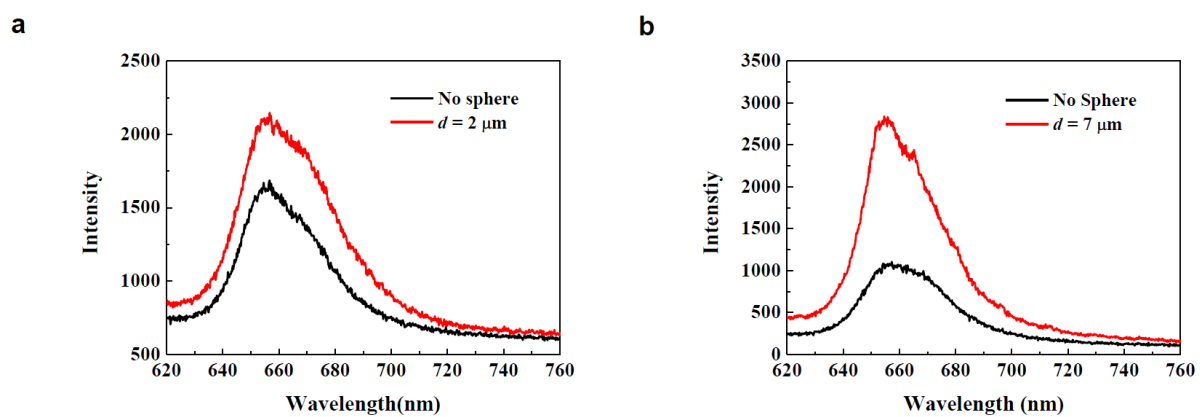


Fig. S2 (a) Photoluminescence enhancement of monolayer MoS₂ coupled to a microsphere with the diameter of 2 μm . **(b)** Photoluminescence enhancement of monolayer MoS₂ coupled to a microsphere with the diameter of 7 μm .

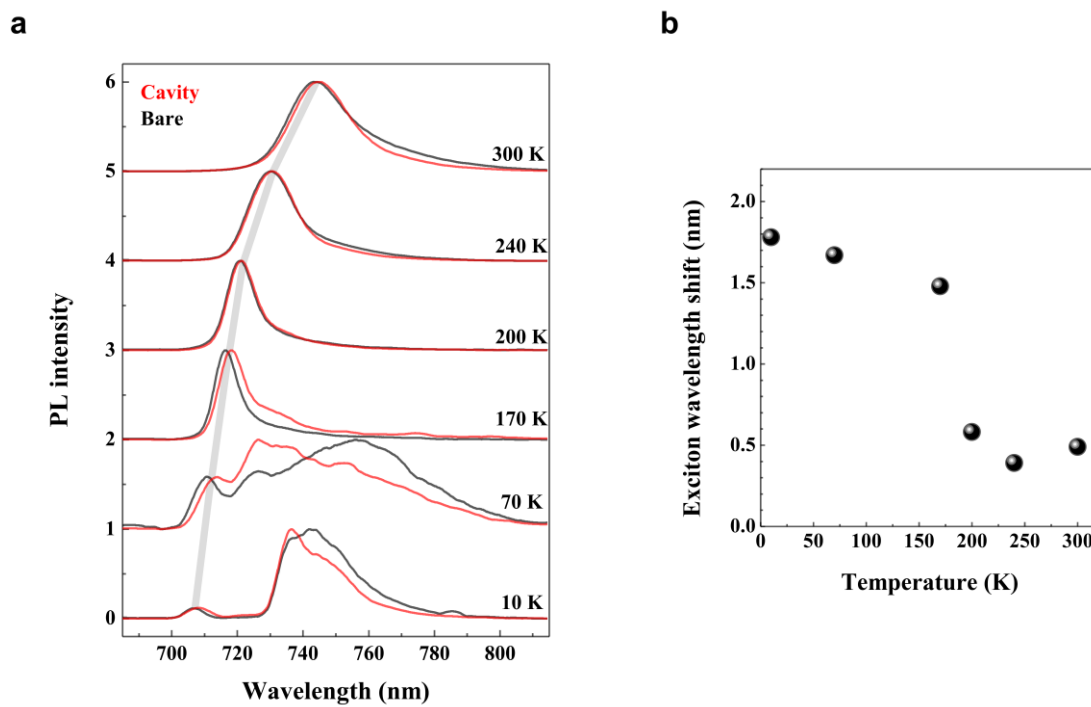


Fig. S3 (a) Temperature dependent PL spectra of the cavity-coupled and bare nearby WSe₂. Exciton emission peak is guided by the grey solid line. **(b)** Wavelength shift of the cavity-coupled exciton peak compared to the bare exciton as a function of temperature.

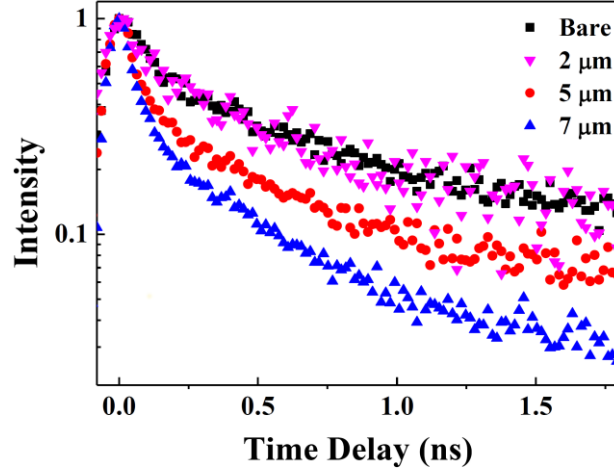


Fig. S4 (a) Time-resolved photoluminescence (TRPL) of monolayer WSe₂ coupled to microspheres with $d = 2, 5,$ and $7 \mu\text{m}$. The measurement performed on bare WSe₂ without a microsphere is also shown for reference.

Sample / $1 \mu\text{m SiO}_2$	A	$\tau_{Th}(\text{ps})$	B	$\tau_X(\text{ps})$
Bare	0.570	125 ± 5	0.422	766 ± 49
$2 \mu\text{m}$	0.435	124 ± 5	0.422	715 ± 80
$5 \mu\text{m}$	0.635	60 ± 2	0.325	515 ± 26
$7 \mu\text{m}$	0.666	46 ± 1	0.326	374 ± 12

Table. T1 Fit parameters of TRPL data shown in **Fig. S3** using the biexponential function $I(t) = A\exp(-t/\tau_{Th}) + B\exp(-t/\tau_X)$. Here, τ_{Th} and τ_X are the thermal dissipation time of hot carriers and the exciton recombination lifetime and A and B are weight factors, respectively.

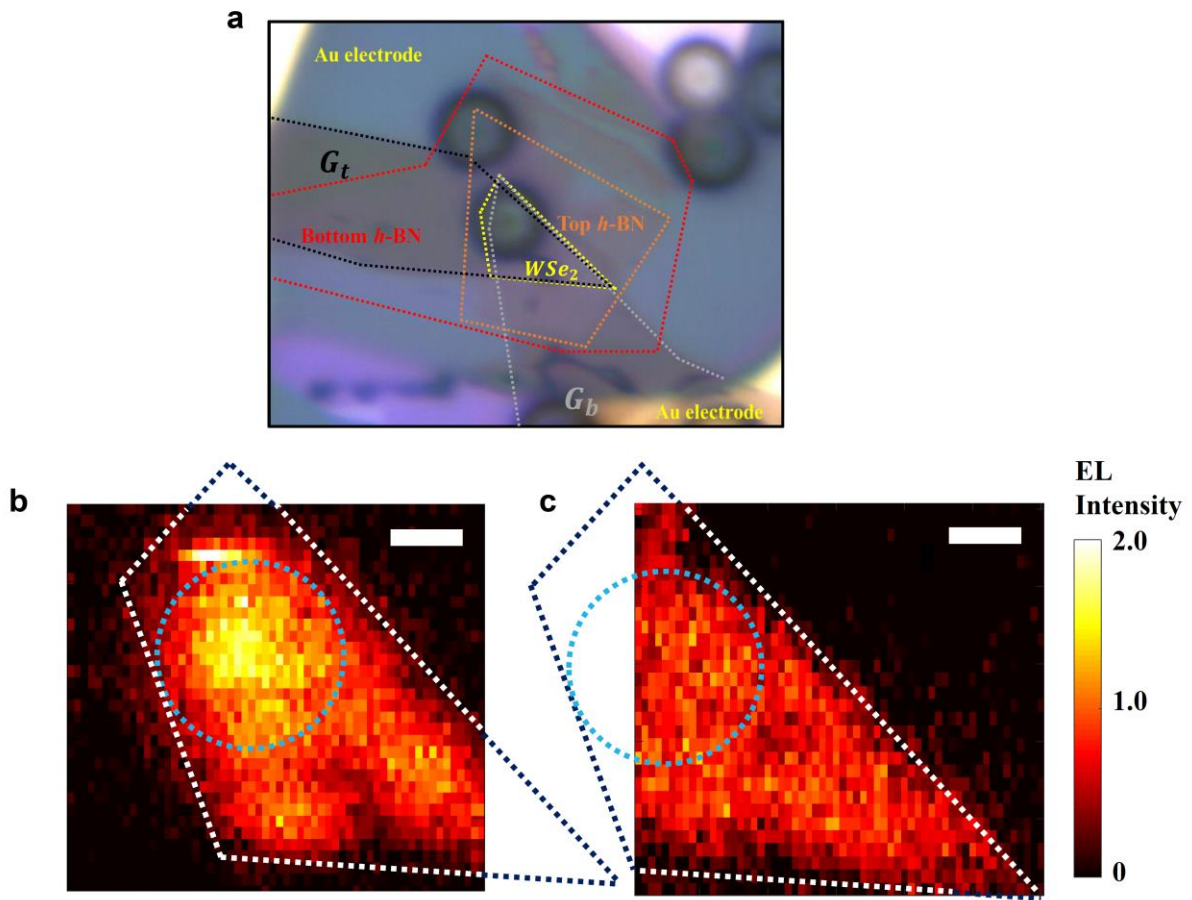


Fig. S5 (a) Optical microscope image of the WSe₂ light-emitting transistor. Monolayer WSe₂ is sandwiched by top and bottom *h*-BN. A voltage is applied through top (G_t) and bottom (G_b) graphene across *h*-BN/WSe₂/*h*-BN structure to induce electron-hole recombination in WSe₂. **(b)** Electroluminescence (EL) scan image of cavity-coupled WSe₂ light-emitting transistor. The white and blue dashed lines refer to the boundaries of WSe₂ and microsphere, respectively. **(c)** EL scan image on the same heterostructure without the microsphere. Scale bar is 3 μm .